

Application Data Sheet

Application Information

Application Type:: Regular
Subject Matter:: Utility
CD-ROM or CD-R?:: None
Computer Readable Form (CRF)?:: No
Title:: SUBSTRATE INSPECTING METHOD AND
SUBSTRATE INSPECTING APPARATUS
USING THE METHOD
Attorney Docket Number:: 044499-0206
Request for Early Publication?:: No
Request for Non-Publication?:: No
Suggested Drawing Figure:: 1
Total Drawing Sheets:: 7
Small Entity?:: No
Petition included?:: No
Secrecy Order in Parent Appl.?:: No

Applicant Information

Applicant Authority Type:: Inventor
Primary Citizenship Country:: Japan
Status:: Full Capacity
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Country of mailing address:: Japan

Correspondence Information

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Representative Information

Representative Customer Number::	22428	
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Domestic Priority Information

Application::	Continuity Type::	Parent Application::	Parent Filing Date::

Foreign Priority Information

Country::	Application number::	Filing Date::	Priority Claimed::
Japan	JP-2003-050357	02/27/2003	Yes

Assignee Information

Assignee name:: Omron Corporation